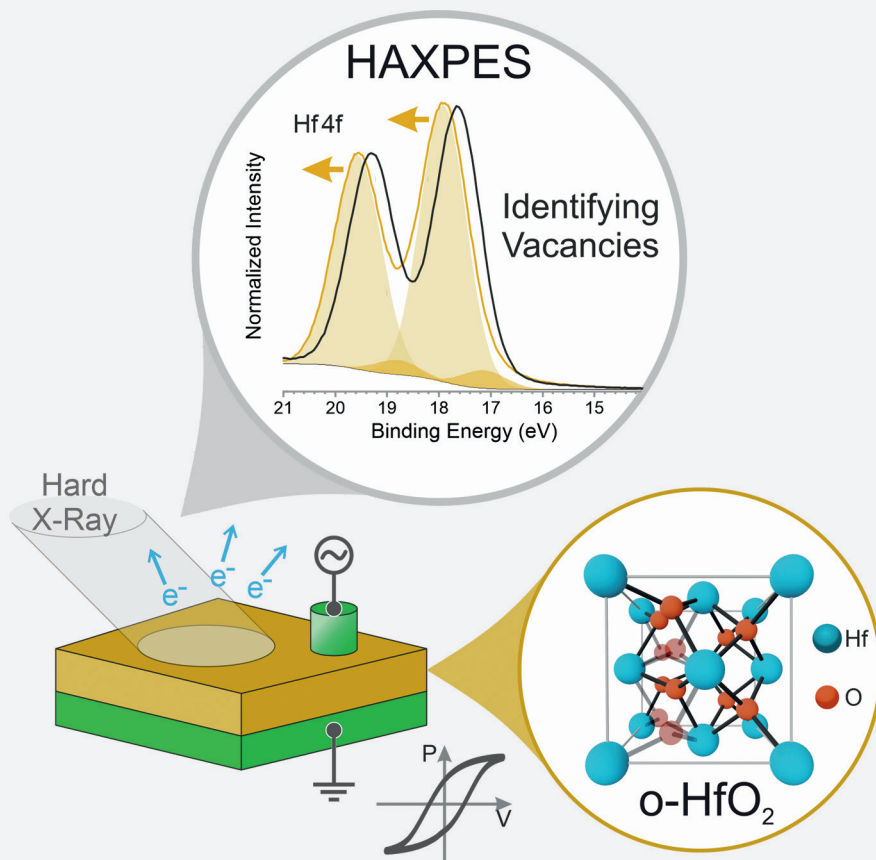




HAXPES study of interface and bulk chemistry of ferroelectric HfO_2 capacitors

Thomas Szyjka

Information

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